PROCEEDINGS OF SPIE

Modeling Aspects in Optical Metrology IX

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Editors

26–28 June 2023
Munich, Germany

Sponsored and Published by
SPIE

Volume 12619

Proceedings of SPIE 0277-786X, V. 12619

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Author(s), "Title of Paper," in *Modeling Aspects in Optical Metrology IX*, edited by Bernd Bodermann, Karsten Frenner, Proc. of SPIE 12619, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X
ISSN: 1996-756X (electronic)

ISBN: 9781510664470
ISBN: 9781510664487 (electronic)

Published by
SPIE
P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time)
SPIE.org
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